- **3-State Outputs Interface Directly With System Bus**

- **Gated Output-Control LInes for Enabling or Disabling the Outputs**

- **Fully Independent Clock Virtually Eliminates Restrictions for Operating in One of Two Modes:**
  - **Parallel Load**
  - **Do Nothing (Hold)**

- **For Application as Bus Buffer Registers**

- **Package Options Include Plastic Small-Outline (D) Packages, Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs**

TYPE	TYPICAL PROPAGATION DELAY TIME	MAXIMUM CLOCK FREQUENCY
'173	23 ns	35 MHz
'LS173A	18 ns	50 MHz

SN54173, SN54LS173A . . . J OR W PACKAGE
SN74173 . . . N PACKAGE
SN74LS173A . . . D or N PACKAGE
(TOP VIEW)

M	1	16 V$_{CC}$
N	2	15 CLR
1Q	3	14 1D
2Q	4	13 2D
3Q	5	12 3D
4Q	6	11 4D
CLK	7	10 $\overline{G}2$
GND	8	9 $\overline{G}1$

SN54LS173A . . . FK PACKAGE
(TOP VIEW)

Top pins: N, M, NC, V$_{CC}$, CLR (3, 2, 1, 20, 19)

1Q	4	18	1D
2Q	5	17	2D
NC	6	16	NC
3Q	7	15	3D
4Q	8	14	4D

Bottom pins: CLK, GND, NC, $\overline{G}1$, $\overline{G}2$ (9, 10, 11, 12, 13)

NC – No internal connection

description

The '173 and 'LS173A 4-bit registers include D-type flip-flops featuring totem-pole 3-state outputs capable of driving highly capacitive or relatively low-impedance loads. The high-impedance third state and increased high-logic-level drive provide these flip-flops with the capability of being connected directly to and driving the bus lines in a bus-organized system without need for interface or pull-up components. Up to 128 of the SN74173 or SN74LS173A outputs can be connected to a common bus and still drive two Series 54/74 or 54LS/74LS TTL normalized loads, respectively. Similarly, up to 49 of the SN54173 or SN54LS173A outputs can be connected to a common bus and drive one additional Series 54/74 or 54LS/74LS TTL normalized load, respectively. To minimize the possibility that two outputs will attempt to take a common bus to opposite logic levels, the output control circuitry is designed so that the average output disable times are shorter than the average output enable times.

Gated enable inputs are provided on these devices for controlling the entry of data into the flip-flops. When both data-enable ($\overline{G}1$, $\overline{G}2$) inputs are low, data at the D inputs are loaded into their respective flip-flops on the next positive transition of the buffered clock input. Gate output-control (M, N) inputs also are provided. When both are low, the normal logic states (high or low levels) of the four outputs are available for driving the loads or bus lines. The outputs are disabled independently from the level of the clock by a high logic level at either output-control input. The outputs then present a high impedance and neither load nor drive the bus line. Detailed operation is given in the function table.

The SN54173 and SN54LS173A are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74173 and SN74LS173A are characterized for operation from 0°C to 70°C.

TEXAS INSTRUMENTS

FUNCTION TABLE

CLR	CLK	DATA ENABLE $\overline{G1}$	DATA ENABLE $\overline{G2}$	DATA D	OUTPUT Q
H	X	X	X	X	L
L	L	X	X	X	Q_0
L	↑	H	X	X	Q_0
L	↑	X	H	X	Q_0
L	↑	L	L	L	L
L	↑	L	L	H	H

When either M or N (or both) is (are) high, the output is disabled to the high-impedance state; however, sequential operation of the flip-flops is not affected.
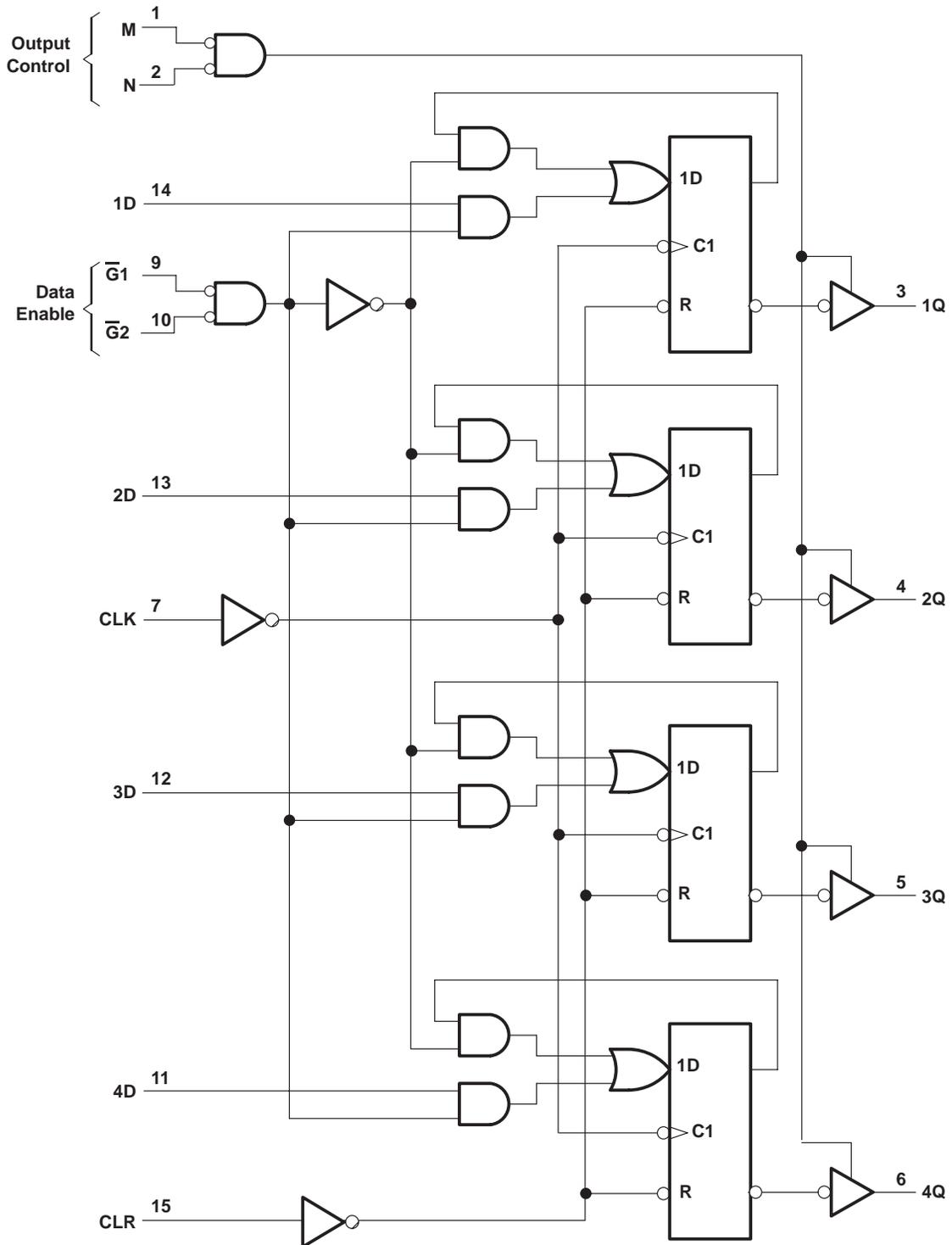
logic symbol†
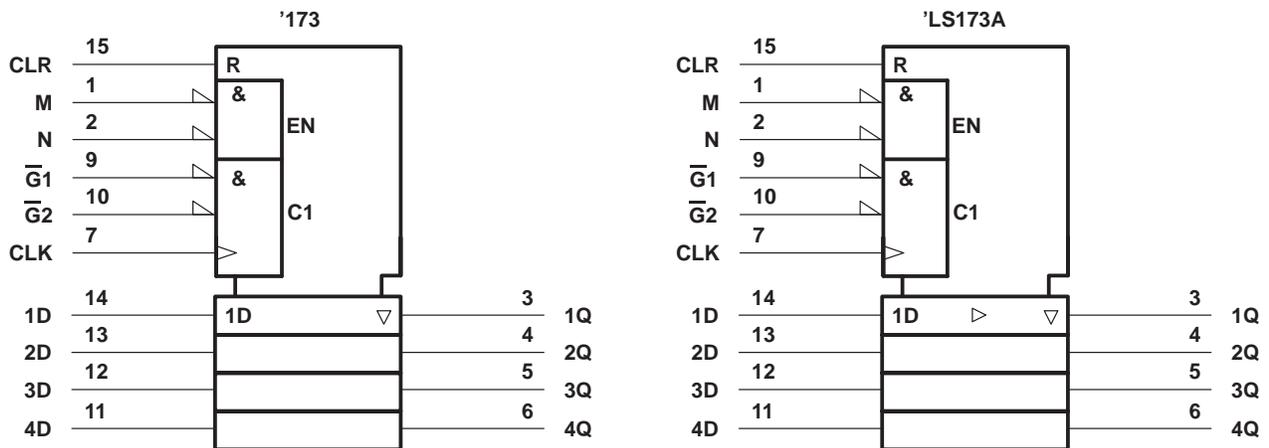
† This symbol is in accordance with ANSI/IEEE Standard 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, N, and W packages.

TEXAS
INSTRUMENTS
POST OFFICE BOX 655303 ● DALLAS, TEXAS 75265

logic diagram (positive logic)

Pin numbers shown are for D, J, N, and W packages.

schematics of inputs and outputs

'173	'LS173A
Equivalent of Each Input	**Equivalent of Each Input**
Typical of All Outputs	**Typical of All Outputs**
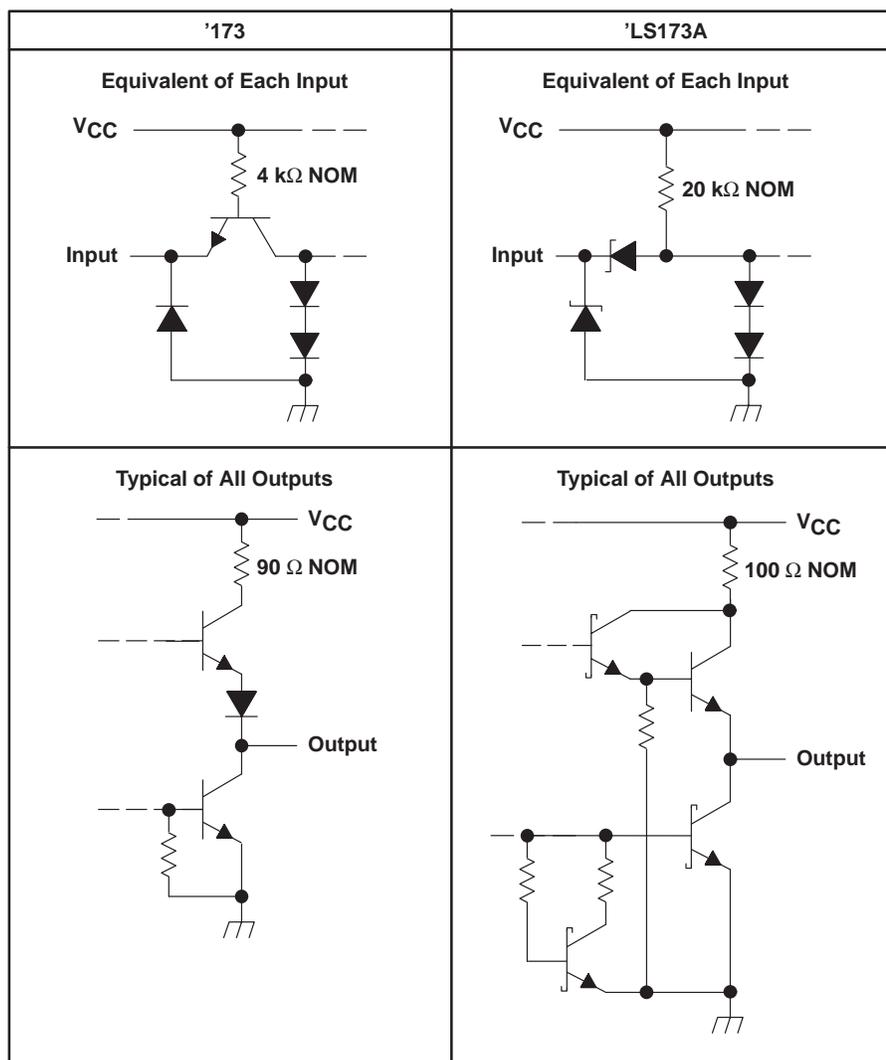
absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V_{CC} (see Note 1) . . . . –0.5 V to 7 V
Input voltage: '173 . . . . –0.5 V to 5.5 V
             'LS173A . . . . –0.5 V to 7 V
Off-state output voltage . . . . –0.5 V to 5.5 V
Package thermal impedance, θ_{JA} (see Note 2): D package . . . . 113°C/W
                                    N package . . . . 78°C/W
Storage temperature range, T_{stg} . . . . –65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. Voltage values are with respect to network ground terminal.
       2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions (see Note 3)

		SN54173			SN74173			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
I_{OH}	High-level output current			−2			−5.2	mA
I_{OL}	Low-level output current			16			16	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs,* literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS†		SN54173			SN74173			UNIT
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IH}	High-level input voltage			2			2			V
V_{IL}	Low-level input voltage					0.8			0.8	V
V_{IK}	Input clamp voltage	V_{CC} = MIN,	I_I = −12 mA			−1.5			−1.5	V
V_{OH}	High-level output voltage	V_{CC} = MIN, V_{IL} = 0.8 V,	V_{IH} = 2 V, I_{OH} = MAX	2.4			2.4			V
V_{OL}	Low-level output voltage	V_{CC} = MIN, V_{IL} = 0.8 V,	V_{IH} = 2 V, I_{OL} = 16 mA			0.4			0.4	V
$I_{O(off)}$	Off-state (high-impedance state) output current	V_{CC} = MAX, V_{IH} = 2 V	V_O = 2.4 V			150			40	µA
			V_O = 0.4 V			−150			−40	
I_I	Input current at maximum input voltage	V_{CC} = MAX,	V_I = 5.5 V			1			1	mA
I_{IH}	High-level input current	V_{CC} = MAX,	V_I = 2.4 V			40			40	µA
I_{IL}	Low-level input current	V_{CC} = MAX,	V_I = 0.4 V			−1.6			−1.6	mA
I_{OS}	Short-circuit output current§	V_{CC} = MAX		−30		−70	−30		−70	mA
I_{CC}	Supply current	V_{CC} = MAX,	See Note 4		50	72		50	72	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time.
NOTE 4: I_{CC} is measured with all outputs open; CLR grounded, following momentary connection to 4.5 V, N, $\overline{G}1$, $\overline{G}2$, and all data inputs grounded; and CLK and M at 4.5 V.

timing requirements over recommended operating conditions (unless otherwise noted)

			SN54173		SN74173		UNIT
			MIN	MAX	MIN	MAX	
f_{clock}	Input clock frequency			25		25	MHz
t_w	Pulse duration	CLK or CLR	20		20		ns
t_{su}	Setup time	Data enable ($\overline{G}1$, $\overline{G}2$)	17		17		ns
		Data	10		10		
		CLR (inactive state)	10		10		
t_h	Hold time	Data enable ($\overline{G}1$, $\overline{G}2$)	2		2		ns
		Data	10		10		

switching characteristics, V_{CC} = 5 V, T_A = 25°C, R_L = 400 Ω (see Figure 1)

PARAMETER		TEST CONDITIONS	SN54173			SN74173			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
f_{max}	Maximum clock frequency	C$_L$ = 50 pF	25	35		25	35		MHz
t_{PHL}	Propagation delay time, high-to-low-level output from clear input			18	27		18	27	ns
t_{PLH}	Propagation delay time, low-to-high-level output from clock input			28	43		28	43	ns
t_{PHL}	Propagation delay time, high-to-low-level output from clock input			19	31		19	31	
t_{PZH}	Output enable time to high level		7	16	30	7	16	30	ns
t_{PZL}	Output enable time to low level		7	21	30	7	21	30	
t_{PHZ}	Output disable time from high level	C$_L$ = 5 pF	3	5	14	3	5	14	ns
t_{PLZ}	Output disable time from low level		3	11	20	3	11	20	

Texas
Instruments

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

recommended operating conditions

		SN54LS173A			SN74LS173A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
I_{OH}	High-level output current			−1			−2.6	mA
I_{OL}	Low-level output current			12			24	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		SN54LS173A			SN74LS173A			UNIT
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
V_{IH}	High-level input voltage			2			2			V
V_{IL}	Low-level input voltage					0.7			0.8	V
V_{IK}	Input clamp voltage	V_{CC} = MIN,	I_I = −18 mA			−1.5			−1.5	V
V_{OH}	High-level output voltage	V_{CC} = MIN, $V_{IL} = V_{IL}$max,	V_{IH} = 2 V, I_{OH} = MAX	2.4	3.4		2.4	3.1		V
V_{OL}	Low-level output voltage	V_{CC} = MIN, V_{IL} = 0.8 V,	I_{OL} = 12 mA		0.25	0.4		0.25	0.4	V
			I_{OL} = 24 mA					0.35	0.5	V
$I_{O(off)}$	Off-state (high-impedance state) output current	V_{CC} = MAX, V_{IH} = 2 V	V_O = 2.7 V			20			20	V
			V_O = 0.4 V			−20			−20	
I_I	Input current at maximum input voltage	V_{CC} = MAX,	V_I = 7 V			0.1			0.1	mA
I_{IH}	High-level input current	V_{CC} = MAX,	V_I = 2.7 V			20			20	µA
I_{IL}	Low-level input current	V_{CC} = MAX,	V_I = 0.4 V			−0.4			−0.4	mA
I_{OS}	Short-circuit output current§	V_{CC} = MAX		−30		−130	−30		−130	mA
I_{CC}	Supply current	V_{CC} = MAX,	See Note 4		19	30		19	24	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time.
NOTE 4: I_{CC} is measured with all outputs open; CLR grounded, following momentary connection to 4.5 V, N, $\overline{G}1$, $\overline{G}2$, and all data inputs grounded; and CLK and M at 4.5 V.

timing requirements over recommended operating conditions (unless otherwise noted)

			SN54LS173A		SN74LS173A		UNIT
			MIN	MAX	MIN	MAX	
f_{clock}	Input clock frequency			30		25	MHz
t_w	Pulse duration	CLK or CLR	25		25		ns
t_{su}	Setup time	Data enable ($\overline{G}1$, $\overline{G}2$)	35		35		ns
		Data	17		17		
		CLR (inactive state)	10		10		
t_h	Hold time	Data enable ($\overline{G}1$, $\overline{G}2$)	0		0		ns
		Data	3		3		

switching characteristics, V_{CC} = 5 V, T_A = 25°C, R_L = 667 Ω (see Figure 2)

PARAMETER		TEST CONDITIONS	SN54LS173A			SN74LS173A			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
f_{max}	Maximum clock frequency		30	50		30	50		MHz
t_{PHL}	Propagation delay time, high-to-low-level output from clear input			26	35		26	35	ns
t_{PLH}	Propagation delay time, low-to-high-level output from clock input	C_L = 45 pF		17	25		17	25	ns
t_{PHL}	Propagation delay time, high-to-low-level output from clock input			22	30		22	30	
t_{PZH}	Output enable time to high level			15	23		15	23	ns
t_{PZL}	Output enable time to low level			18	27		18	27	
t_{PHZ}	Output disable time from high level	C_L = 5 pF		11	20		11	20	ns
t_{PLZ}	Output disable time from low level			11	17		11	17	

TEXAS
INSTRUMENTS

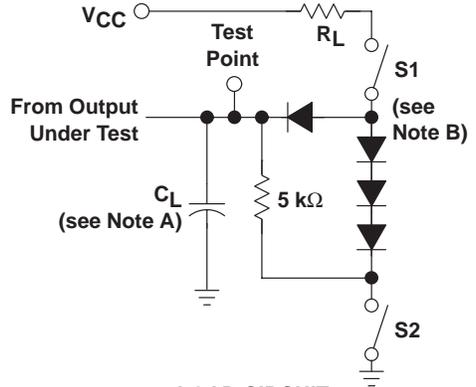POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

PARAMETER MEASUREMENT INFORMATION
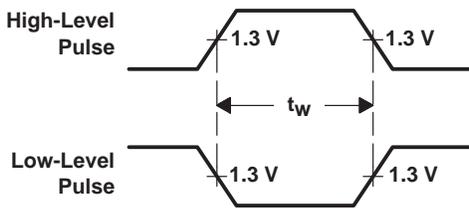## SERIES 54/74 AND 54S/74S DEVICES
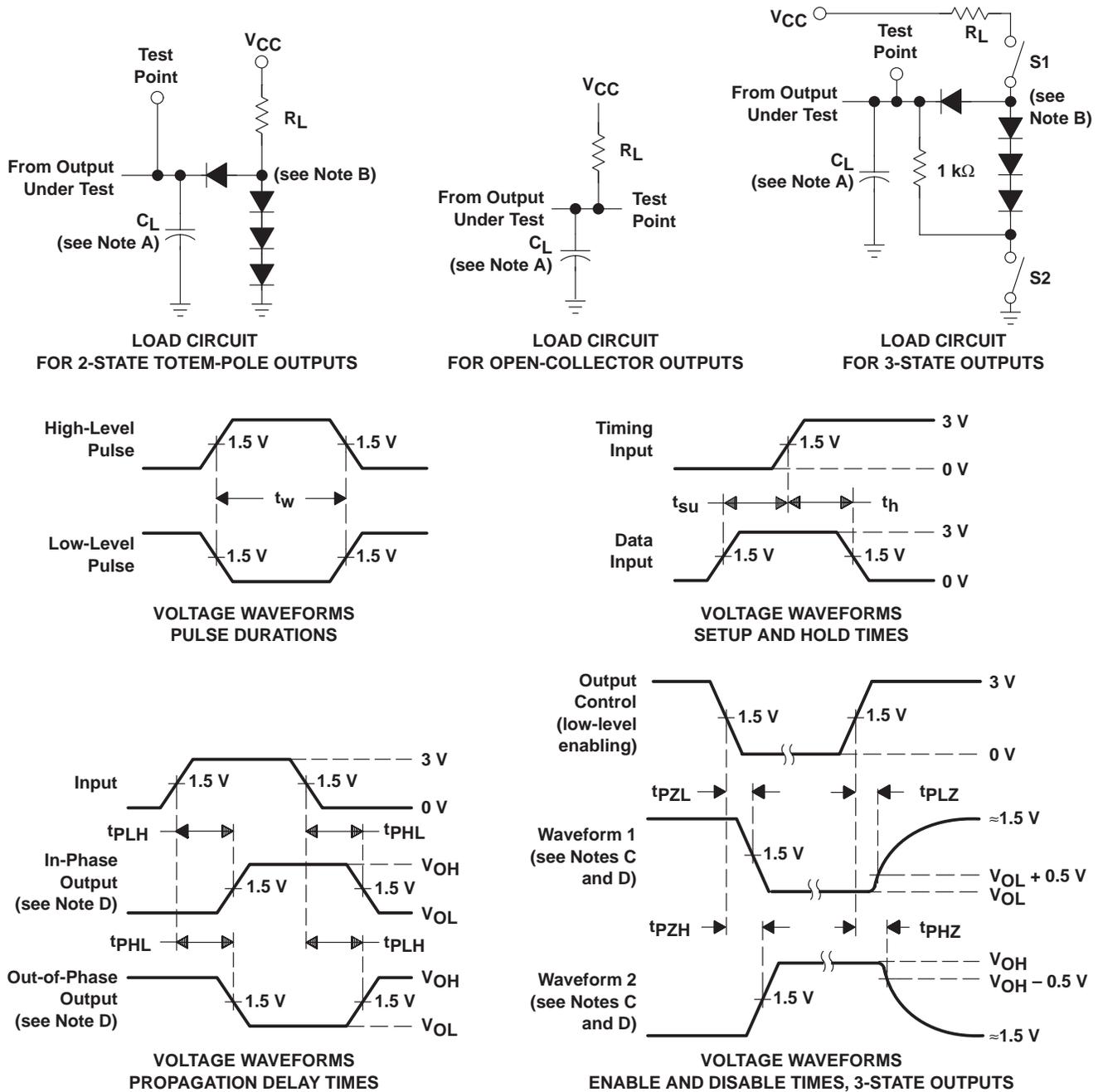
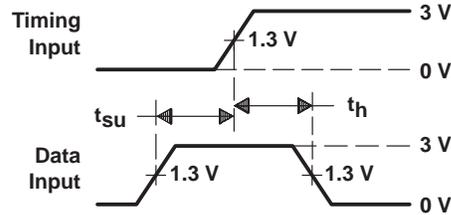**LOAD CIRCUIT
FOR 2-STATE TOTEM-POLE OUTPUTS**

**LOAD CIRCUIT
FOR OPEN-COLLECTOR OUTPUTS**

**LOAD CIRCUIT
FOR 3-STATE OUTPUTS**

**VOLTAGE WAVEFORMS
PULSE DURATIONS**

**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**

**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**

**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS**

NOTES: A. C_L includes probe and jig capacitance.
　　　 B. All diodes are 1N3064 or equivalent.
　　　 C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
　　　　　 Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
　　　 D. S1 and S2 are closed for t_{PLH}, t_{PHL}, t_{PHZ}, and t_{PLZ}; S1 is open and S2 is closed for t_{PZH}; S1 is closed and S2 is open for t_{PZL}.
　　　 E. All input pulses are supplied by generators having the following characteristics: PRR $\leq$ 1 MHz, $Z_O \approx$ 50 Ω, t_r and $t_f \leq$ 7 ns for Series
　　　　　 54/74 devices and t_r and $t_f \leq$ 2.5 ns for Series 54S/74S devices.
　　　 F. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
SERIES 54LS/74LS DEVICES

**LOAD CIRCUIT FOR
2-STATE
TOTEM-POLE OUTPUTS**

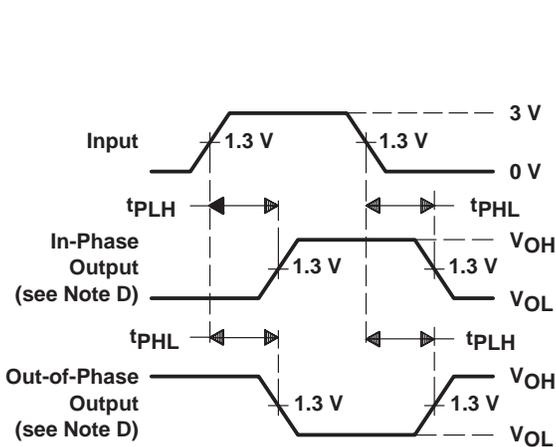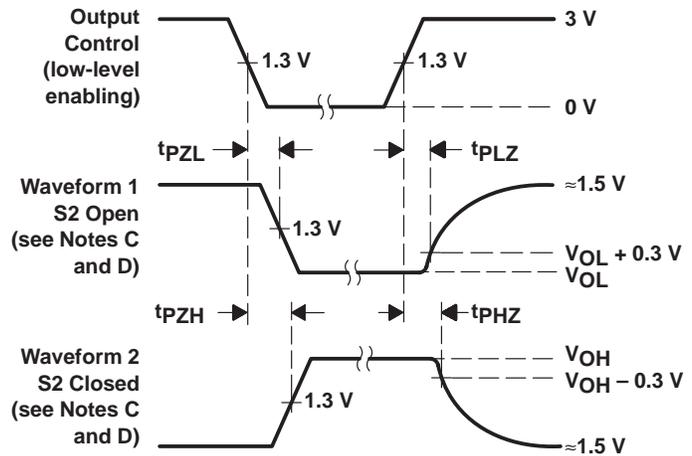**LOAD CIRCUIT
FOR OPEN-COLLECTOR OUTPUTS**

**LOAD CIRCUIT
FOR 3-STATE OUTPUTS**

**VOLTAGE WAVEFORMS
PULSE DURATIONS**

**VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES**

**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**

**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS**

NOTES: A. C_L includes probe and jig capacitance.
        B. All diodes are 1N3064 or equivalent.
        C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
           Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
        D. S1 and S2 are closed for t_{PLH}, t_{PHL}, t_{PHZ}, and t_{PLZ}; S1 is open and S2 is closed for t_{PZH}; S1 is closed and S2 is open for t_{PZL}.
        E. Phase relationships between inputs and outputs have been chosen arbitrarily for these examples.
        F. All input pulses are supplied by generators having the following characteristics: PRR $\leq$ 1 MHz, $Z_O \approx$ 50 Ω, $t_r \leq$ 15 ns, $t_f \leq$ 6 ns.
        G. The outputs are measured one at a time with one input transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms

**TEXAS
INSTRUMENTS**

POST OFFICE BOX 655303 ● DALLAS, TEXAS 75265

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.